



# 16-BIT, 1.25-MSPS, UNIPOLAR PSEUDO-DIFFERENTIAL INPUT, MICROPOWER SAMPLING ANALOG-TO-DIGITAL CONVERTER WITH PARALLEL INTERFACE

#### **FEATURES**

- Unipolar Pseudo-Differential Input, 0 V to V<sub>ref</sub>
- 16-Bit NMC at 1.25 MSPS
- ±2 LSB INL Max, -1/+1.5 LSB DNL
- 86 dB SNR, -90 dB THD at 100 kHz Input
- Zero Latency
- Internal 4.096-V Reference
- High-Speed Parallel Interface
- Single 5-V Analog Supply
- Wide I/O Supply: 2.7 V to 5.25 V
- Low Power: 155 mW at 1.25 MHz Typ
- Pin Compatible With ADS8411/8401
- 48-Pin TQFP Package

#### **APPLICATIONS**

- DWDM
- Instrumentation
- High-Speed, High-Resolution, Zero Latency Data Acquisition Systems
- Transducer Interface
- Medical Instruments
- Communications

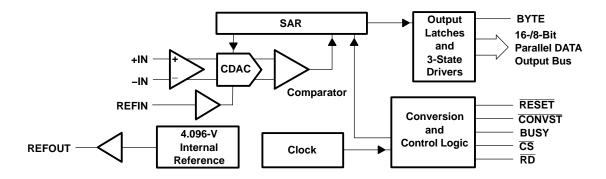
#### **DESCRIPTION**

The ADS8405 is a 16-bit, 1.25-MHz A/D converter with an internal 4.096-V reference. The device includes a 16-bit capacitor-based SAR A/D converter with inherent sample and hold. The ADS8405 offers a full 16-bit interface and an 8-bit option where data is read using two 8-bit read cycles if necessary.

The ADS8405 has a unipolar pseudo-differential input. It is available in a 48-lead TQFP package and is characterized over the industrial -40°C to 85°C temperature range.

#### **High Speed SAR Converter Family**

Type/Speed	500 kHz	~600 kHz	750 kHz	1 MHz	1.25 MHz	2 MHz	3 MHz	4 MHz
18-Bit Pseudo-Diff	ADS8383	ADS8381						
16-Bit Pseudo-Dili		ADS8380 (S)						
18-Bit Pseudo-Bipolar, Fully Diff		ADS8382 (S)						
16-Bit Pseudo-Diff			ADS8371		ADS8401/05	ADS8411		
16-Bit Pseudo-Bipolar, Fully Diff					ADS8402/06	ADS8412		
14-Bit Pseudo-Diff					ADS7890 (S)		ADS7891	
12-Bit Pseudo-Diff				ADS7886				ADS7881





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



## ORDERING INFORMATION(1)

MODEL	MAXIMUM INTEGRAL LINEARITY (LSB)	MAXIMUM DIFFERENTIAL LINEARITY (LSB)	NO MISSING CODES RESOLUTION (BIT)	PACKAGE TYPE	PACKAGE DESIGNATOR	TEMPERATURE RANGE	ORDERING INFORMATION	TRANSPORT MEDIA QUANTITY
ADS8405I	-4 to +4	-2 to +2	15	48 Pin TOFP	PFB	–40°C to 85°C	ADS8405IPFBT	Tape and reel 250
AD364031	-4 10 +4	-2 to +2	15	40 FIII TQI F	FFB	-40 C to 65 C	ADS8405IPFBR	Tape and reel 1000
ADS940EID	ADS8405IB		16	48 Pin TQFP	PFB	-40°C to 85°C	ADS8405IBPFBT	Tape and reel 250
AD36403IB			16	40 FIII TQFF	FFB	-40 C to 65 C	ADS8405IBPFBR	Tape and reel 1000

<sup>(1)</sup> For the most current specifications and package information, refer to our website at www.ti.com.

#### **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range unless otherwise noted (1)

				UNIT
		+IN to AGNE	)	-0.4 V to +VA + 0.1 V
		-IN to AGND	1	-0.4 V to 0.5 V
	Voltage	+VA to AGNI	)	-0.3 V to 7 V
		+VBD to BD0	GND	-0.3 V to 7 V
		+VA to +VBD	)	−0.3 V to 2.55 V
	Digital input volta	ge to BDGND		-0.3 V to +VBD + 0.3 V
	Digital output volt	tage to BDGN	D	-0.3 V to +VBD + 0.3 V
T <sub>A</sub>	Operating free-ai	r temperature	range	-40°C to 85°C
T <sub>stg</sub>	Storage temperat	ture range		−65°C to 150°C
	Junction tempera	ture (T <sub>J</sub> max)		150°C
	TOED pookogo	Power dissip	ation	$(T_{J}Max - T_{A})/\theta_{JA}$
	TQFP package	$\theta_{JA}$ thermal impedance		86°C/W
	Load tomporature	a coldorina	Vapor phase (60 sec)	215°C
	Lead temperature, soldering		Infrared (15 sec)	220°C

<sup>(1)</sup> Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



### **SPECIFICATIONS**

 $T_{A} = -40^{\circ}\text{C to } 85^{\circ}\text{C}, \text{ +VA} = 5 \text{ V}, \text{ +VBD} = 3 \text{ V or 5 V}, V_{ref} = 4.096 \text{ V}, f_{SAMPLE} = 1.25 \text{ MHz (unless otherwise noted)}$ 

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
ANALO	G INPUT					<u></u>		
	Full-scale input voltage (	(1)	+IN - (-IN)	0		$V_{ref}$	V	
	AL 1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.		+IN	-0.2		V <sub>ref</sub> + 0.2	.,	
	Absolute input voltage		-IN	-0.2		0.2	V	
	Input capacitance				25		pF	
	Input leakage current				0.5		nA	
SYSTE	M PERFORMANCE							
	Resolution				16		Bits	
	No missing codes	ADS8405I		15			Bits	
	No missing codes	ADS8405IB		16			DIIS	
INII	Integral linearity (2)(3)  ADS8405			-4	±2	4	LSB	
INL	integral lineanty (=7(3)	ADS8405IB		-2	±1	2	LOD	
DNII	Differential linearity	ADS8405I		-2	±1	2	LCD	
DNL	Differential linearity	ADS8405IB		-1	±0.75	1.5	LSB	
_	Off at annual(1)	ADS8405I		-3	±1	3	mV	
Eo	Offset error <sup>(4)</sup>	ADS8405IB		-1.5	±0.5	1.5	mV	
_	(4)(5)	ADS8405I		-0.15		0.15	0/50	
E <sub>G</sub> Gain error <sup>(4)(5)</sup>		ADS8405IB		-0.098		0.98	%FS	
	Noise				60		μV RMS	
	DC Power supply rejection	on ratio	At FFFFh output code, +VA = 4.75 V to 5.25 V, V <sub>ref</sub> = 4.096 V <sup>(4)</sup>		2		LSB	
SAMPL	ING DYNAMICS					<u>"</u>		
	Conversion time			500		650	ns	
	Acquisition time			150			ns	
	Throughput rate					1.25	MHz	
	Aperture delay				2		ns	
	Aperture jitter				25		ps	
	Step response				100		ns	
	Overvoltage recovery				100		ns	
DYNAN	IIC CHARACTERISTICS					"		
TUD	Tatal hammania diatantian	. (6)	VIN = 4 V <sub>p-p</sub> at 100 kHz		-90		dB	
THD	Total harmonic distortion	1(0)	VIN = 4 V <sub>p-p</sub> at 500 kHz		-88.5		dB	
SNR	Signal-to-noise ratio		VIN = 4 V <sub>p-p</sub> at 100 kHz		86		dB	
SINAD	Signal-to-noise + distorti	on	VIN = 4 V <sub>p-p</sub> at 100 kHz		85		dB	
0500 0 1 1 1		VIN = 4 V <sub>p-p</sub> at 100 kHz		90		dB		
SFDR Spurious free dynamic range			VIN = 4 V <sub>p-p</sub> at 500 kHz		88		dB	
	-3dB Small signal bandw	vidth			5		MHz	
EXTER	NAL VOLTAGE REFERE		<u> </u>					
	Reference voltage at RE			2.5	4.096	4.2	V	
	Reference resistance (7)				500		kΩ	

<sup>(1)</sup> Ideal input span, does not include gain or offset error.

LSB means least significant bit

This is endpoint INL, not best fit.

Measured relative to an ideal full-scale input (+IN – (-IN)) of 4.096 V. This specification does not include the internal reference voltage error and drift.

Calculated on the first nine harmonics of the input frequency.

<sup>(6)</sup> (7) Can vary ±20%



## **SPECIFICATIONS** (continued)

 $T_A = -40$  °C to 85 °C, +VA = 5 V, +VBD = 3 V or 5 V,  $V_{ref} = 4.096$  V,  $f_{SAMPLE} = 1.25$  MHz (unless otherwise noted)

PARAMETER			TEST CONDITIONS	MIN	TYP	MAX	UNIT
INTER	NAL REFERENCE OUTPU	Т		•		<u> </u>	
	Internal reference start-u	p time	From 95% (+VA), with 1-µF storage capacitor			120	ms
V <sub>ref</sub> range		IOUT = 0	4.065	4.096	4.13	V	
	Source current		Static load			10	μΑ
	Line regulation		+VA = 4.75 V to 5.25 V		0.6		mV
	Drift		IOUT = 0		36		PPM/C
DIGITA	AL INPUT/OUTPUT			•		<u> </u>	
	Logic family - CMOS						
$V_{IH}$	High-level input voltage		I <sub>IH</sub> = 5 μA	+VBD - 1	+VBD + 0.3		
$V_{IL}$	Low-level input voltage		I <sub>IL</sub> = 5 μA	-0.3		0.8 V	
$V_{OH}$	High-level output voltage		I <sub>OH</sub> = 2 TTL loads	+VBD - 0.6		+VBD	V
$V_{OL}$	Low-level output voltage		I <sub>OL</sub> = 2 TTL loads	0		0.4	
	Data format - straight bin	ary					
POWE	R SUPPLY REQUIREMEN	TS	·			<u> </u>	
	Dawer augustus	+VBD		2.7	3	5.25	V
	Power supply voltage	+VA		4.75	5	5.25	V
	+VA Supply current (8)	•	f <sub>s</sub> = 1.25 MHz		31	34	mA
	Power dissipation <sup>(8)</sup>		f <sub>s</sub> = 1.25 MHz		155	170	mW
TEMPI	ERATURE RANGE			•		,	
	Operating free-air			-40		85	°C

<sup>(8)</sup> This includes only VA+ current. +VBD current is typically 1 mA with 5-pF load capacitance on output pins.



## TIMING CHARACTERISTICS

All specifications typical at  $-40^{\circ}$ C to  $85^{\circ}$ C, +VA = +VBD = 5 V (1)(2)(3)

	PARAMETER	MIN	TYP MAX	UNIT
t <sub>CONV</sub>	Conversion time	500	650	ns
t <sub>ACQ</sub>	Acquisition time	150		ns
t <sub>pd1</sub>	CONVST low to BUSY high		40	ns
t <sub>pd2</sub>	Propagation delay time, end of conversion to BUSY low		5	ns
t <sub>w1</sub>	Pulse duration, CONVST low	20		ns
t <sub>su1</sub>	Setup time, CS low to CONVST low	0		ns
t <sub>w2</sub>	Pulse duration, CONVST high	20		ns
	CONVST falling edge jitter		10	ps
t <sub>w3</sub>	Pulse duration, BUSY signal low	Min(t <sub>ACQ</sub> )		ns
t <sub>w4</sub>	Pulse duration, BUSY signal high		610	ns
t <sub>h1</sub>	Hold time, first data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low	40		ns
t <sub>d1</sub>	Delay time, $\overline{CS}$ low to $\overline{RD}$ low (or BUSY low to $\overline{RD}$ low when $\overline{CS} = 0$ )	0		ns
t <sub>su2</sub>	Setup time, RD high to CS high	0		ns
t <sub>w5</sub>	Pulse duration, $\overline{\text{RD}}$ low	50		ns
t <sub>en</sub>	Enable time, $\overline{\text{RD}}$ low (or $\overline{\text{CS}}$ low for read cycle) to data valid		20	ns
t <sub>d2</sub>	Delay time, data hold from RD high	0		ns
t <sub>d3</sub>	Delay time, BYTE rising edge or falling edge to data valid	2	20	ns
t <sub>w6</sub>	Pulse duration, RD high	20		ns
t <sub>w7</sub>	Pulse duration, CS high	20		ns
t <sub>h2</sub>	Hold time, last $\overline{\text{RD}}$ (or $\overline{\text{CS}}$ for read cycle ) rising edge to $\overline{\text{CONVST}}$ falling edge	50		ns
t <sub>su3</sub>	Setup time, BYTE transition to RD falling edge	0		ns
t <sub>h3</sub>	Hold time, BYTE transition to RD falling edge	0		ns
t <sub>dis</sub>	Disable time, RD high (CS high for read cycle) to 3-stated data bus		20	ns
t <sub>d5</sub>	Delay time, end of conversion to MSB data valid		10	ns
t <sub>su4</sub>	Byte transition setup time, from BYTE transition to next BYTE transition	50		ns
t <sub>d6</sub>	Delay time, CS rising edge to BUSY falling edge	50		ns
t <sub>d7</sub>	Delay time, BUSY falling edge to CS rising edge	50		ns
t <sub>su(AB)</sub>	Setup time, from the falling edge of $\overline{\text{CONVST}}$ (used to start the valid conversion) to the next falling edge of $\overline{\text{CONVST}}$ (when $\overline{\text{CS}} = 0$ and $\overline{\text{CONVST}}$ used to abort) or to the next falling edge of $\overline{\text{CS}}$ (when $\overline{\text{CS}}$ is used to abort)	60	500	ns
t <sub>su5</sub>	Setup time, falling edge of CONVST to read valid data (MSB) from current conversion	$MAX(t_{CONV}) + MAX(t_{d5})$		ns
t <sub>h4</sub>	Hold time, data (MSB) from previous conversion hold valid from falling edge of CONVST		MIN(t <sub>CONV</sub> )	ns

<sup>(1)</sup> All input signals are specified with  $t_r = t_f = 5$  ns (10% to 90% of +VBD) and timed from a voltage level of  $(V_{IL} + V_{IH})/2$ . (2) See timing diagrams.

<sup>(2)</sup> See timing diagrams.(3) All timings are measured with 20-pF equivalent loads on all data bits and BUSY pins.



## TIMING CHARACTERISTICS

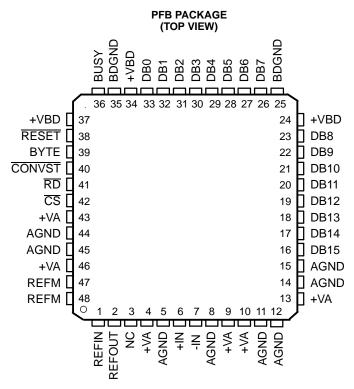
All specifications typical at  $-40^{\circ}$ C to  $85^{\circ}$ C, +VA = 5 V, +VBD = 3 V<sup>(1)(2)(3)</sup>

	PARAMETER	MIN	TYP MAX	UNIT
t <sub>CONV</sub>	Conversion time	500	650	ns
t <sub>ACQ</sub>	Acquisition time	150		ns
t <sub>pd1</sub>	CONVST low to BUSY high		50	ns
t <sub>pd2</sub>	Propagation delay time, end of conversion to BUSY low		10	ns
t <sub>w1</sub>	Pulse duration, CONVST low	20		ns
t <sub>su1</sub>	Setup time, CS low to CONVST low	0		ns
t <sub>w2</sub>	Pulse duration, CONVST high	20		ns
	CONVST falling edge jitter		10	ps
t <sub>w3</sub>	Pulse duration, BUSY signal low	Min(t <sub>ACQ</sub> )		ns
t <sub>w4</sub>	Pulse duration, BUSY signal high		610	ns
t <sub>h1</sub>	Hold time, first data bus transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low	40		ns
t <sub>d1</sub>	Delay time, $\overline{CS}$ low to $\overline{RD}$ low (or BUSY low to $\overline{RD}$ low when $\overline{CS} = 0$ )	0		ns
t <sub>su2</sub>	Setup time, RD high to CS high	0		ns
t <sub>w5</sub>	Pulse duration, RD low	50		ns
t <sub>en</sub>	Enable time, RD low (or CS low for read cycle) to data valid		30	ns
t <sub>d2</sub>	Delay time, data hold from RD high	0		ns
t <sub>d3</sub>	Delay time, BYTE rising edge or falling edge to data valid	2	30	ns
t <sub>w6</sub>	Pulse duration, RD high	20		ns
t <sub>w7</sub>	Pulse duration, CS high	20		ns
t <sub>h2</sub>	Hold time, last $\overline{\text{RD}}$ (or $\overline{\text{CS}}$ for read cycle ) rising edge to $\overline{\text{CONVST}}$ falling edge	50		ns
t <sub>su3</sub>	Setup time, BYTE transition to RD falling edge	0		ns
t <sub>h3</sub>	Hold time, BYTE transition to RD falling edge	0		ns
t <sub>dis</sub>	Disable time, RD high (CS high for read cycle) to 3-stated data bus		30	ns
t <sub>d5</sub>	Delay time, end of conversion to MSB data valid		20	ns
t <sub>su4</sub>	Byte transition setup time, from BYTE transition to next BYTE transition	50		ns
t <sub>d6</sub>	Delay time, CS rising edge to BUSY falling edge	50		ns
t <sub>d7</sub>	Delay time, BUSY falling edge to CS rising edge	50		ns
t <sub>su(AB)</sub>	Setup time, from the falling edge of $\overline{\text{CONVST}}$ (used to start the valid conversion) to the next falling edge of $\overline{\text{CONVST}}$ (when $\overline{\text{CS}}$ = 0 and $\overline{\text{CONVST}}$ used to abort) or to the next falling edge of $\overline{\text{CS}}$ (when $\overline{\text{CS}}$ is used to abort)	70	500	ns
t <sub>su5</sub>	Setup time, falling edge of CONVST to read valid data (MSB) from current conversion	$MAX(t_{CONV}) + MAX(t_{d5})$		ns
t <sub>h4</sub>	Hold time, data (MSB) from previous conversion hold valid from falling edge of CONVST		MIN(t <sub>CONV</sub> )	ns

 <sup>(1)</sup> All input signals are specified with t<sub>r</sub> = t<sub>f</sub> = 5 ns (10% to 90% of +VBD) and timed from a voltage level of (V<sub>IL</sub> + V<sub>IH</sub>)/2.
 (2) See timing diagrams.
 (3) All timings are measured with 10-pF equivalent loads on all data bits and BUSY pins.



### **PIN ASSIGNMENTS**



NC - No connection

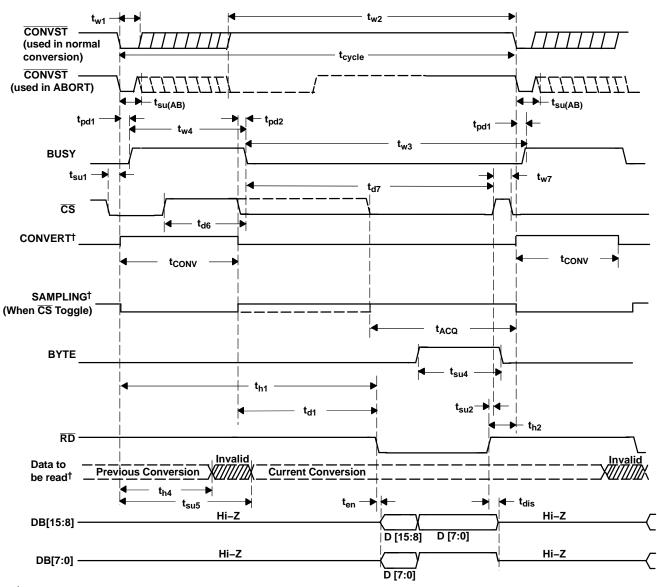


### **Terminal Functions**

NAME	NO.	I/O		DESCRIPTION					
AGND	5, 8, 11, 12, 14, 15, 44, 45	_	Analog ground						
BDGND	25, 35	_	Digital ground for bus interface digital supply						
BUSY	36	0	Status output. High when a co	nversion is in progress.					
BYTE	39	I	Byte select input. Used for 8-b significant bits is folded back to		ck 1: Low byte D[7:0] of the 16 most ignificant pins DB[15:8].				
CONVST	40	I	Convert start. The falling edge period.	of this input ends the acqui	sition period and starts the hold				
CS	42	I	Chip select. The falling edge of	f this input starts the acquisi	ition period.				
Data Bua			8-Bit E	Bus	16-Bit Bus				
Data Bus			BYTE = 0	BYTE = 1	BYTE = 0				
DB15	16	0	D15 (MSB)	D7	D15 (MSB)				
DB14	17	0	D14	D6	D14				
DB13	18	0	D13	D5	D13				
DB12	19	0	D12	D4	D12				
DB11	20	0	D11	D3	D11				
DB10	21	0	D10	D2	D10				
DB9	22	0	D9	D1	D9				
DB8	23	0	D8	D0 (LSB)	D8				
DB7	26	0	D7	All ones	D7				
DB6	27	0	D6	All ones	D6				
DB5	28	0	D5	All ones	D5				
DB4	29	0	D4	All ones	D4				
DB3	30	0	D3	All ones	D3				
DB2	31	0	D2	All ones	D2				
DB1	32	0	D1	All ones	D1				
DB0	33	0	D0 (LSB)	All ones	D0 (LSB)				
-IN	7	I	Inverting input channel						
+IN	6	I	Noninverting input channel						
NC	3	-	No connection						
REFIN	1	I	Reference input						
REFM	47, 48	I	Reference ground						
REFOUT	2	0	Reference output. Add 1-µF capacitor between the REFOUT pin and REFM pin when the internal reference is used.						
RESET	38	I	Current conversion is aborted and output latches are cleared (set to zeros) when this pin is asserted low. RESET works independently of CS.						
RD	41	I	Synchronization pulse for the parallel output. When $\overline{\text{CS}}$ is low, this serves as the output enable and puts the previous conversion result on the bus.						
+VA	4, 9, 10, 13, 43, 46	_		Analog power supplies, 5-V dc					
+VBD	24, 34, 37	-	Digital power supply for bus						



### **TIMING DIAGRAMS**



<sup>†</sup>Signal internal to device

Figure 1. Timing for Conversion and Acquisition Cycles With CS and RD Toggling



## **TIMING DIAGRAMS (continued)**

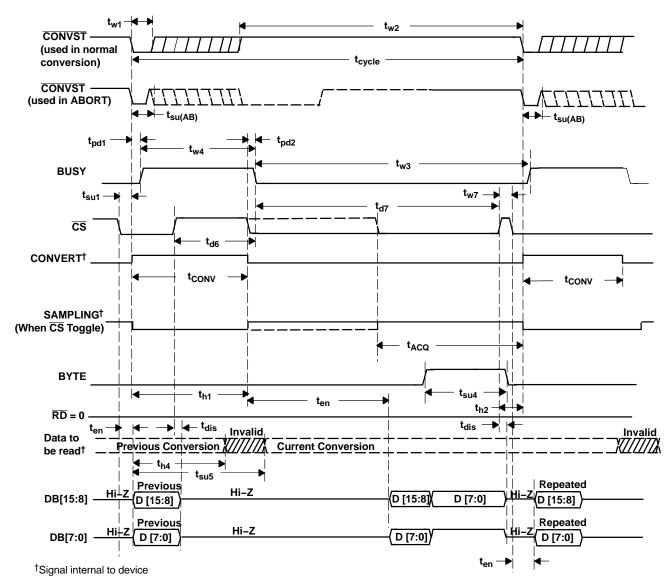


Figure 2. Timing for Conversion and Acquisition Cycles With  $\overline{\text{CS}}$  Toggling,  $\overline{\text{RD}}$  Tied to BDGND



## **TIMING DIAGRAMS (continued)**

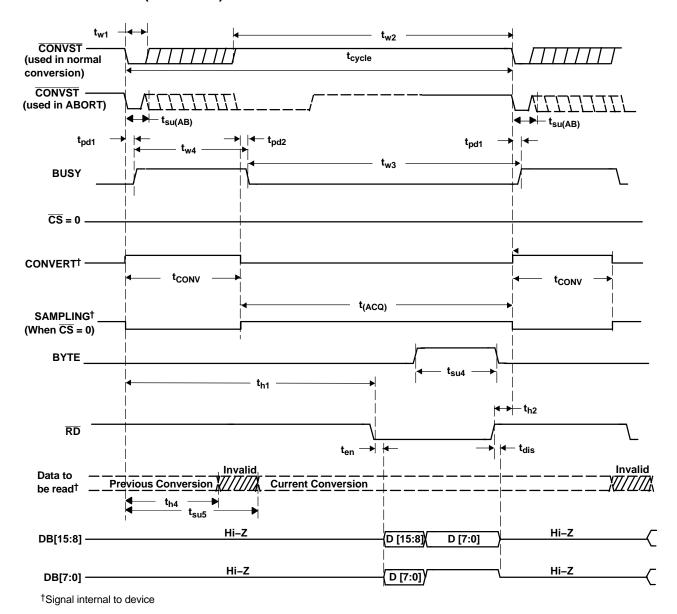
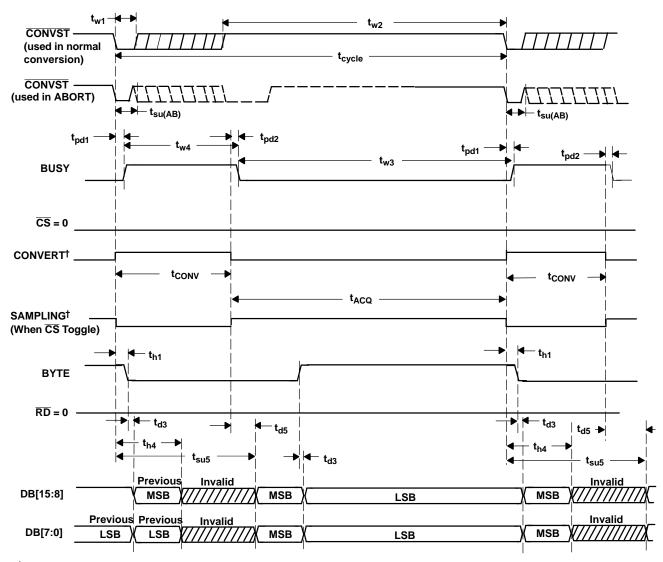


Figure 3. Timing for Conversion and Acquisition Cycles With  $\overline{\text{CS}}$  Tied to BDGND,  $\overline{\text{RD}}$  Toggling



## **TIMING DIAGRAMS (continued)**



<sup>†</sup>Signal internal to device

Figure 4. Timing for Conversion and Acquisition Cycles With  $\overline{\text{CS}}$  and  $\overline{\text{RD}}$  Tied to BDGND—Auto Read

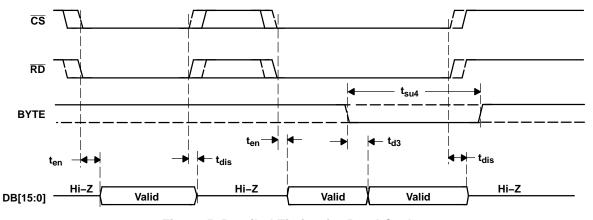


Figure 5. Detailed Timing for Read Cycles



#### TYPICAL CHARACTERISTICS

At  $-40^{\circ}$ C to  $85^{\circ}$ C, +VA = 5 V, +VBD = 5 V, REFIN = 4.096 V (internal reference used) and  $f_{sample}$  = 1.25 MHz (unless otherwise noted)

## HISTOGRAM (DC Code Spread) HALF SCALE 131071 CONVERSIONS

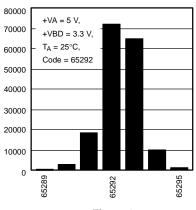


Figure 6.

## SIGNAL-TO-NOISE AND DISTORTION vs FREE-AIR TEMPERATURE

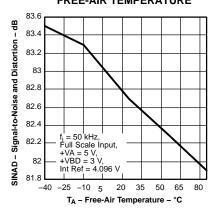


Figure 8.

#### SIGNAL-TO-NOISE RATIO vs FREE-AIR TEMPERATURE

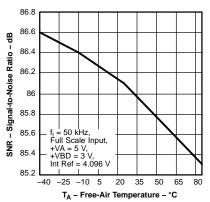


Figure 7.

## EFFECTIVE NUMBER OF BITS vs FREE-AIR TEMPERATURE

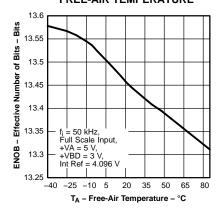


Figure 9.



## SPURIOUS FREE DYNAMIC RANGE vs FREE-AIR TEMPERATURE

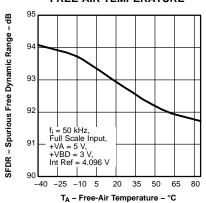


Figure 10.

## SIGNAL-TO-NOISE RATIO VS INPUT FREQUENCY

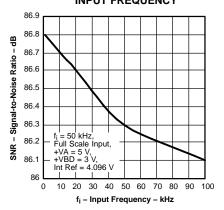


Figure 12.

## SIGNAL-TO-NOISE AND DISTORTION VS INPUT FREQUENCY

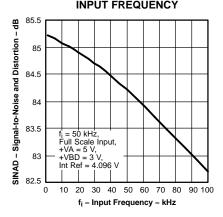


Figure 14.

## TOTAL HARMONIC DISTORTION vs FREE-AIR TEMPERATURE

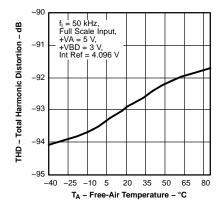


Figure 11.

## EFFECTIVE NUMBER OF BITS VS INPUT FREQUENCY

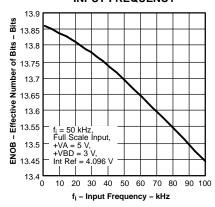


Figure 13.

## SPURIOUS FREE DYNAMIC RANGE vs INPUT FREQUENCY

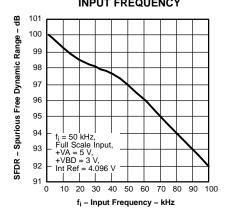


Figure 15.



# TOTAL HARMONIC DISTORTION VS INPUT FREQUENCY

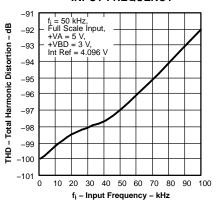


Figure 16.

#### GAIN ERROR vs SUPPLY VOLTAGE

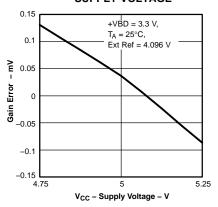


Figure 18.

#### INTERNAL VOLTAGE REFERENCE vs FREE-AIR TEMPERATURE

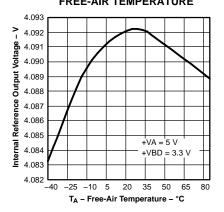


Figure 20.

#### SUPPLY CURRENT vs SAMPLE RATE

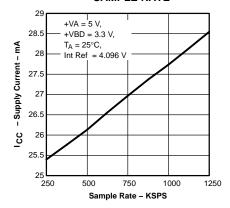


Figure 17.

#### OFFSET ERROR VS SUPPLY VOLTAGE

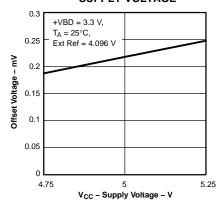


Figure 19.

#### GAIN ERROR vs FREE-AIR TEMPERATURE

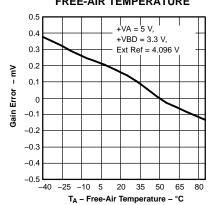


Figure 21.



#### OFFSET ERROR vs FREE-AIR TEMPERATURE

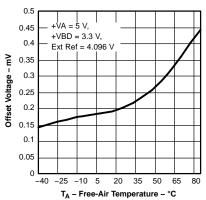


Figure 22.

## DIFFERENTIAL NONLINEARITY vs FREE-AIR TEMPERATURE

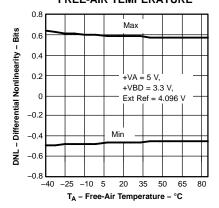


Figure 24.

## DIFFERENTIAL NONLINEARITY VS REFERENCE VOLTAGE

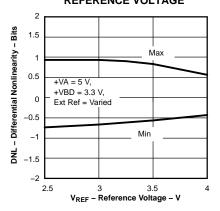


Figure 26.

#### SUPPLY CURRENT vs FREE-AIR TEMPERATURE

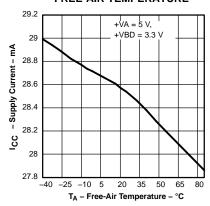


Figure 23.

## INTEGRAL NONLINEARITY vs FREE-AIR TEMPERATURE

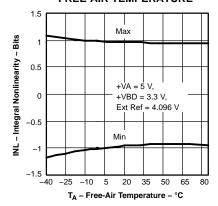


Figure 25.

## INTEGRAL NONLINEARITY vs REFERENCE VOLTAGE

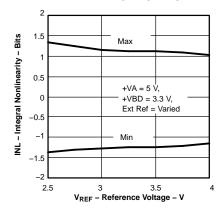
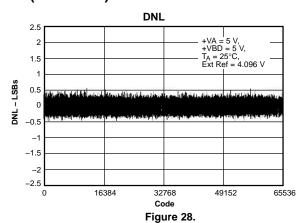
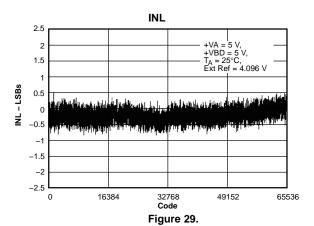
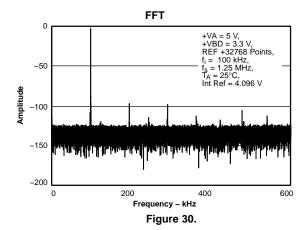


Figure 27.











#### **APPLICATION INFORMATION**

#### MICROCONTROLLER INTERFACING

#### ADS8405 to 8-Bit Microcontroller Interface

Figure 31 shows a parallel interface between the ADS8405 and a typical microcontroller using the 8-bit data bus. The BUSY signal is used as a falling-edge interrupt to the microcontroller.

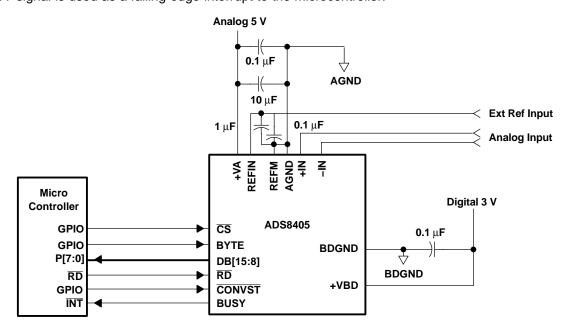


Figure 31. ADS8405 Application Circuitry (Using an External Reference)

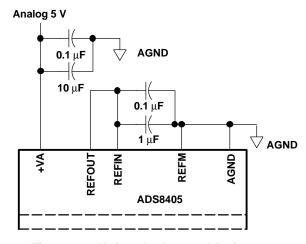


Figure 32. Using the Internal Reference

#### PRINCIPLES OF OPERATION

The ADS8405 is a high-speed successive approximation register (SAR) analog-to-digital converter (ADC). The architecture is based on charge redistribution, which inherently includes a sample/hold function. See Figure 31 for the application circuit for the ADS8405.

The conversion clock is generated internally. The conversion time of 650 ns is capable of sustaining a 1.25-MHz throughput.



### PRINCIPLES OF OPERATION (continued)

The analog input is provided to two input pins: +IN and -IN. When a conversion is initiated, the differential input on these pins is sampled on the internal capacitor array. While a conversion is in progress, both inputs are disconnected from any internal function.

#### REFERENCE

The ADS8405 can operate with an external reference with a range from 2.5 V to 4.2 V. A 4.096-V internal reference is included. When an internal reference is used, pin 2 (REFOUT) should be connected to pin 1 (REFIN) with a 0.1-µF decoupling capacitor and a 1-µF storage capacitor between pin 2 (REFOUT) and pins 47 and 48 (REFM) (see Figure 32). The internal reference of the converter is double buffered. If an external reference is used, the second buffer provides isolation between the external reference and the CDAC. This buffer is also used to recharge all of the capacitors of the CDAC during conversion. Pin 2 (REFOUT) can be left unconnected (floating) if an external reference is used.

### **ANALOG INPUT**

When the converter enters hold mode, the voltage difference between the +IN and -IN inputs is captured on the internal capacitor array. The voltage on the -IN input is limited between -0.2 V and 0.2 V, allowing the input to reject small signals which are common to both the +IN and -IN inputs. The +IN input has a range of -0.2 V to  $V_{ref}$  + 0.2 V. The input span (+IN - (-IN)) is limited to 0 V to  $V_{ref}$ .

The input current on the analog inputs depends upon a number of factors: sample rate, input voltage, and source impedance. Essentially, the current into the ADS8405 charges the internal capacitor array during the sample period. After this capacitance has been fully charged, there is no further input current. The source of the analog input voltage must be able to charge the input capacitance (25 pF) to an 16-bit settling level within the acquisition time (150 ns) of the device. When the converter goes into hold mode, the input impedance is greater than 1 G $\Omega$ .

Care must be taken regarding the absolute analog input voltage. To maintain the linearity of the converter, the +IN and -IN inputs and the span (+IN - (-IN)) should be within the limits specified. Outside of these ranges, the converter's linearity may not meet specifications. To minimize noise, low bandwidth input signals with low-pass filters should be used.

Care should be taken to ensure that the output impedance of the sources driving the +IN and -IN inputs are matched. If this is not observed, the two inputs could have different setting times. This may result in offset error, gain error, and linearity error which varies with temperature and input voltage. A typical input circuit using TI's THS4031 is shown in Figure 33.

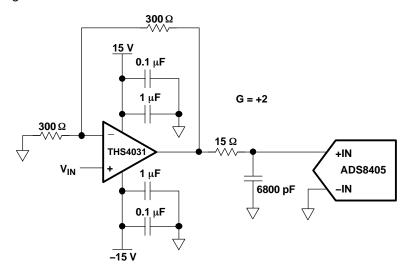


Figure 33. Using the THS4031 with the ADS8405



# PRINCIPLES OF OPERATION (continued) DIGITAL INTERFACE

#### **Timing And Control**

See the timing diagrams in the specifications section for detailed information on timing signals and their requirements.

The ADS8405 uses an internal oscillator generated clock which controls the conversion rate and in turn the throughput of the converter. No external clock input is required.

Conversions are initiated by bringing the  $\overline{\text{CONVST}}$  pin low for a minimum of 20 ns (after the 20 ns minimum requirement has been met, the  $\overline{\text{CONVST}}$  pin can be brought high) while  $\overline{\text{CS}}$  is low. The ADS8405 switches from the sample to the hold mode on the falling edge of the  $\overline{\text{CONVST}}$  command. A clean and low jitter falling edge of this signal is important to the performance of the converter. The BUSY output is brought high after  $\overline{\text{CONVST}}$  goes low. BUSY stays high throughout the conversion process and returns low when the conversion has ended.

Sampling starts as soon as the conversion is over when  $\overline{CS}$  is tied low or starts with the falling edge of  $\overline{CS}$  when BUSY is low.

Both  $\overline{RD}$  and  $\overline{CS}$  can be high during and before a conversion with one exception ( $\overline{CS}$  must be low when  $\overline{CONVST}$  goes low to initiate a conversion). Both the  $\overline{RD}$  and  $\overline{CS}$  pins are brought low in order to enable the parallel output bus with the conversion.

### **Reading Data**

The ADS8405 outputs full parallel data in straight binary format as shown in Table 1. The parallel output is active when  $\overline{CS}$  and  $\overline{RD}$  are both low. There is a minimal quiet zone requirement around the falling edge of  $\overline{CONVST}$ . This is 50 ns prior to the falling edge of  $\overline{CONVST}$  and 40 ns after the falling edge. No data read should be attempted within this zone. Any other combination of  $\overline{CS}$  and  $\overline{RD}$  sets the parallel output to 3-state. BYTE is used for multiword read operations. BYTE is used whenever lower bits of the converter result are output on the higher byte of the bus. Refer to Table 1 for ideal output codes.

**DESCRIPTION ANALOG VALUE DIGITAL OUTPUT** Full scale range  $+V_{ref}$ STRAIGHT BINARY (+V<sub>ref</sub>)/65536 Least significant bit (LSB) **BINARY CODE HEX CODE** Full scale  $(+V_{ref}) - 1 LSB$ 1111 1111 1111 1111 **FFFF** 1000 0000 0000 0000 Midscale (+V<sub>ref</sub>)/2 8000 Midscale - 1 LSB  $(+V_{ref})/2 - 1 LSB$ 0111 1111 1111 1111 7FFF 0 V 0000 0000 0000 0000 0000

Table 1. Ideal Input Voltages and Output Codes

The output data is a full 16-bit word (D15 – D0) on the DB15 – DB0 pins (MSB-LSB) if BYTE is low.

The result may also be read on an 8-bit bus for convenience. This is done by using only pins DB15 – DB8. In this case two reads are necessary: the first as before, leaving BYTE low and reading the 8 most significant bits on pins DB15 – DB8, then bringing BYTE high. When BYTE is high, the low bits (D7 – D0) appear on pins DB15 – D8.

These multiword read operations can be done with multiple active RD (toggling) or with RD tied low for simplicity.

#### **Conversion Data Readout**

BYTE	DATA READ OUT						
BIIC	DB15-DB8 Pins	DB7-DB0 Pins					
High	D7-D0	All one's					
Low	D15-D8	D7-D0					



#### RESET

RESET is an asynchronous active low input signal (that works independently of  $\overline{CS}$ ). Minimum  $\overline{RESET}$  low time is 25 ns. The current conversion is aborted no later than 50 ns after the converter is in reset mode. In addition, all output latches are cleared (set to zero's) after  $\overline{RESET}$ . The converter goes back to normal operation mode no later than 20 ns after the  $\overline{RESET}$  input is brought high.

The converter starts the first sampling period 20 ns after the rising edge of RESET. Any sampling period except for the one immediately after a RESET is started with the falling edge of the previous BUSY signal or the falling edge of CS, whichever is later.

Another way to reset the device is through the use of the combination of  $\overline{CS}$  and  $\overline{CONVST}$ . This is useful when the dedicated  $\overline{RESET}$  pin is tied to the system reset but there is a need to abort only the conversion in a specific converter. Since the BUSY signal is held high during the conversion, either one of these conditions triggers an internal self-clear reset to the converter just the same as a reset via the dedicated  $\overline{RESET}$  pin. The reset does not have to be cleared as for the dedicated  $\overline{RESET}$  pin. A reset can be started with either of the two following steps.

- Issue a CONVST when CS is low and a conversion is in progress. The falling edge of CONVST must satisfy
  the timing as specified by the timing parameter t<sub>su(AB)</sub> specified in the timing characteristics table to ensure a
  reset. The falling edge of CONVST starts a reset. The timing is the same as a reset using the dedicated
  RESET pin except the instance of the falling edge is replaced by the falling edge of CONVST.
- Issue a S while a conversion is in progress. The falling edge of S must satisfy the timing as specified by the timing parameter t<sub>su(AB)</sub> specified in the timing characteristics table to ensure a reset. The falling edge of S causes a reset. The timing is the same as a reset using the dedicated ESET pin except the instance of the falling edge is replaced by the falling edge of S.

#### **POWER-ON INITIALIZATION**

RESET is not required after power on. An internal power-on reset circuit generates the reset. To ensure that all of the registers are cleared, the three conversion cycles must be given to the converter after power on.

#### **LAYOUT**

For optimum performance, care should be taken with the physical layout of the ADS8405 circuitry.

As the ADS8405 offers single-supply operation, it is often used in close proximity with digital logic, microcontrollers, microprocessors, and digital signal processors. The more digital logic present in the design and the higher the switching speed, the more difficult it is to achieve good performance from the converter.

The basic SAR architecture is sensitive to glitches or sudden changes on the power supply, reference, ground connections, and digital inputs that occur just prior to latching the output of the analog comparator. Thus, driving any single conversion for an n-bit SAR converter, there are at least n *windows* in which large external transient voltages can affect the conversion result. Such glitches might originate from switching power supplies, nearby digital logic, or high power devices.

The degree of error in the digital output depends on the reference voltage, layout, and the exact timing of the external event.

On average, the ADS8405 draws very little current from an external reference, as the reference voltage is internally buffered. If the reference voltage is external and originates from an op amp, make sure that it can drive the bypass capacitor or capacitors without oscillation. A 0.1-µF bypass capacitor and a 1-µF storage capacitor are recommended from pin 1 (REFIN) directly to pin 48 (REFM). REFM and AGND should be shorted on the same ground plane under the device.

The AGND and BDGND pins should be connected to a clean ground point. In all cases, this should be the analog ground. Avoid connections which are close to the grounding point of a microcontroller or digital signal processor. If required, run a ground trace directly from the converter to the power supply entry point. The ideal layout consists of an analog ground plane dedicated to the converter and associated analog circuitry.



As with the AGND connections, +VA should be connected to a 5-V power supply plane or trace that is separate from the connection for digital logic until they are connected at the power entry point. Power to the ADS8405 should be clean and well bypassed. A 0.1-µF ceramic bypass capacitor should be placed as close to the device as possible. See Table 2 for the placement of the capacitor. In addition, a 1-µF to 10-µF capacitor is recommended. In some situations, additional bypassing may be required, such as a 100-µF electrolytic capacitor or even a Pi filter made up of inductors and capacitors—all designed to essentially low-pass filter the 5-V supply, removing the high frequency noise.

**Table 2. Power Supply Decoupling Capacitor Placement** 

POWER SUPPLY PLANE SUPPLY PINS	CONVERTER ANALOG SIDE	CONVERTER DIGITAL SIDE
Pin pairs that require shortest path to decoupling capacitors	(4,5), (8,9), (10,11), (13,15), (43,44), (45,46)	(24,25), (34, 35)
Pins that require no decoupling	12, 14	37

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#### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
ADS8405IBPFBR	ACTIVE	TQFP	PFB	48	1000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	ADS8405I B	Samples
ADS8405IBPFBT	ACTIVE	TQFP	PFB	48	250	RoHS & Green	Call TI	Level-2-260C-1 YEAR	-40 to 85	ADS8405I B	Samples
ADS8405IBPFBTG4	ACTIVE	TQFP	PFB	48	250	RoHS & Green	Call TI	Level-2-260C-1 YEAR	-40 to 85	ADS8405I B	Samples
ADS8405IPFBR	ACTIVE	TQFP	PFB	48	1000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	ADS8405I	Samples
ADS8405IPFBT	ACTIVE	TQFP	PFB	48	250	RoHS & Green	Call TI	Level-2-260C-1 YEAR	-40 to 85	ADS8405I	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



## PACKAGE OPTION ADDENDUM

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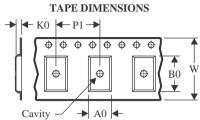
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## **PACKAGE MATERIALS INFORMATION**

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### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	_	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ADS8405IBPFBR	TQFP	PFB	48	1000	330.0	16.4	9.6	9.6	1.5	12.0	16.0	Q2
ADS8405IPFBR	TQFP	PFB	48	1000	330.0	16.4	9.6	9.6	1.5	12.0	16.0	Q2



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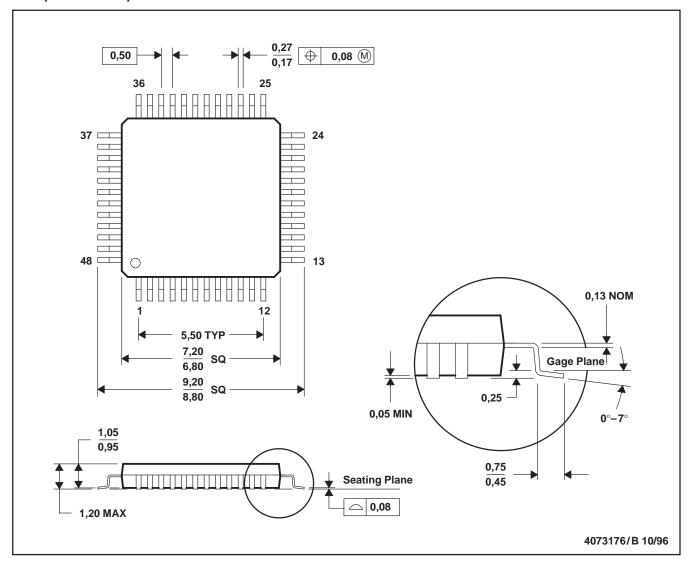


#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ADS8405IBPFBR	TQFP	PFB	48	1000	350.0	350.0	43.0
ADS8405IPFBR	TQFP	PFB	48	1000	350.0	350.0	43.0

## PFB (S-PQFP-G48)

#### PLASTIC QUAD FLATPACK

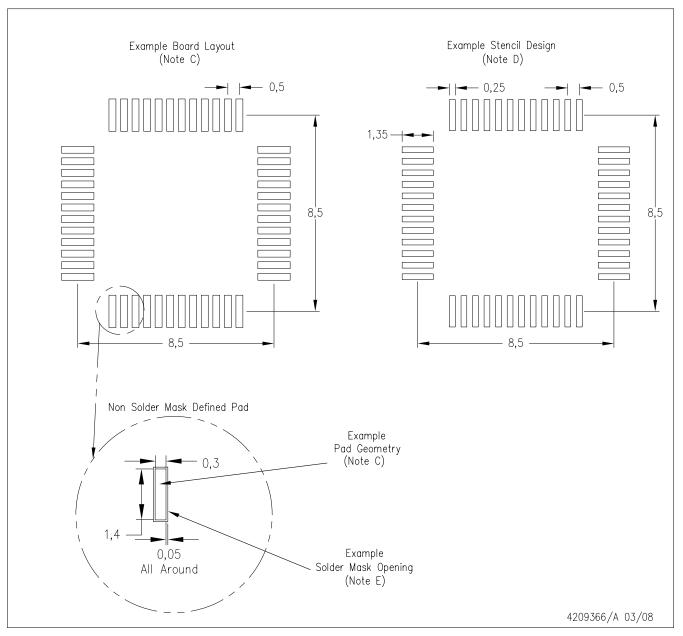


NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-026

## PFB (S-PQFP-G48)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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